
**Non-destructive testing — Standard
test method for determining residual
stresses by neutron diffraction**

*Essais non destructifs — Méthode normalisée de détermination des
contraintes résiduelles par diffraction de neutrons*

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see www.iso.org/patents).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see www.iso.org/iso/foreword.html.

This document was prepared by Technical Committee ISO/TC 135, *Non-destructive testing*, Subcommittee SC 5, *Radiographic Testing*.

This first edition cancels and replaces ISO/TS 21432:2005, which has been technically revised. It also incorporates the Technical Corrigendum ISO/TS 21432:2005/Cor 1:2008. Furthermore this document replaces ISO/TTA3:2001.

The main changes compared to ISO/TS 21432 are as follows:

- [Figures 1](#) and [5](#) were replaced with updated, more suitable versions. The keys for several figures were updated in order to better reflect and explain the content of the figures.
- [5.4](#) was rearranged to emphasize the distinction between monochromatic instruments and time-of-flight instruments.
- The former [Clause 7](#) became [Clause 6](#) and vice versa. The new order reflects better the real order of steps taken in the preparation of a measurement.
- [7.6](#) was updated to provide additional details on the determination of the stress-free reference value.
- [Clause 10](#) was slightly modified and the references to the ISO/IEC Guides relevant to uncertainty determination were updated.
- [11.7](#) was added in order to include uncertainties and errors in the reporting.
- [A.5.4](#) was revised and amended to provide more information on grain size effects and the possibilities to mitigate these.
- [A.9](#) was added to explain the calculation of stresses in the case of macroscopically anisotropic material.
- The Bibliography was updated by including a few new references.

- Throughout the document minor revisions of the text were implemented in order to correct small errors and to improve the clarity.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

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Introduction

Neutron diffraction is a non-destructive method that can be employed for determining residual stresses in crystalline materials. It can also be used to determine internal stresses in samples subjected to applied stresses. The procedure can be employed for determining stresses within the interior of materials and adjacent to surfaces. It requires specimens or engineering components to be transported to a neutron source. Elastic strains are derived from the measurements, which in turn are converted into stresses. The purpose of this document is to provide an International Standard for reliably determining stresses that are relevant to engineering applications.

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